

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination FLESCH ET AL.	
		Examiner SARGON N. NANO	Art Unit 2157	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0114204	05-2005	Kim et al.	705/014
*	B	US-7,139,732	11-2006	Desenberg, Roger Marx	705/37
*	C	US-2003/0158957	08-2003	Abdolsalehi, Ali	709/231
*	D	US-6,925,495	08-2005	Hegde et al.	709/223
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.